

Notice of References Cited

Application/Control No.

10/540,688

Applicant(s)/Patent Under
Reexamination
COENE ET AL.

Examiner

Dac V. Ha

Art Unit

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Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,487,293	11-2002	Sako et al.	380/201
*	C	US-5,778,139	07-1998	Kim, Tae-eung	386/81
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.